



YOUSHANG SEMICONDUCTOR

**设计研发新型功率器件**

**各类小信号开关**

**中低压及高压大电流等场效应管**

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企业微信二维码



企业QQ二维码

## Product Summary

$BV_{DSS}$	$R_{DS(ON)}$ Max	$I_D$ Max $T_C = +25^\circ C$
30V	11m $\Omega$ @ $V_{GS} = 10V$	50A
	13m $\Omega$ @ $V_{GS} = 4.5V$	45A

## Features and Benefits

- Low  $R_{DS(ON)}$  – Ensures On State Losses Are Minimized
- Small Form Factor Thermally Efficient Package Enables Higher Density End Products
- Occupies Just 33% of The Board Area Occupied by SO-8 Enabling Smaller End Product
- Wettable Flank for Improved Optical Inspection

## Description and Applications

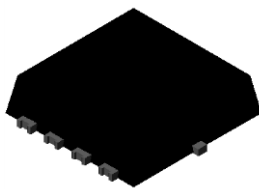
This MOSFET is designed to minimize the on-state resistance ( $R_{DS(ON)}$ ) yet maintain superior switching performance, making it ideal for high efficiency power management applications.

- Backlighting
- Power Management Functions
- DC-DC Converters

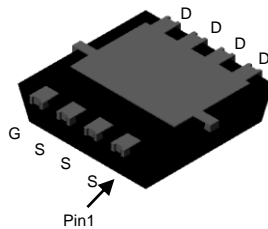
## Mechanical Data

- Case: PowerDI<sup>®</sup>3333-8
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections Indicator: See Diagram
- Terminals: Finish — Matte Tin Annealed over Copper Leadframe. Solderable per MIL-STD-202, Method 208 (E3)
- Weight: 0.03 grams (Approximate)

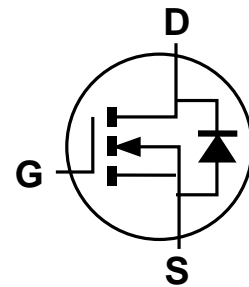
PowerDI3333-8 (SWP) (Type UX)



Top View



Bottom View



Equivalent Circuit

**Maximum Ratings** (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Value	Unit	
Drain-Source Voltage	V <sub>DSS</sub>	30	V	
Gate-Source Voltage	V <sub>GSS</sub>	±20	V	
Continuous Drain Current V <sub>GS</sub> = 10V	I <sub>D</sub>	T <sub>A</sub> = +25°C	12	A
		T <sub>A</sub> = +70°C	10	A
	I <sub>D</sub>	T <sub>C</sub> = +25°C	50	A
T <sub>C</sub> = +70°C		37	A	
Maximum Continuous Body Diode Forward Current (Note 5)	I <sub>S</sub>	3	A	
Pulsed Drain Current (10μs Pulse, Duty Cycle = 1%)	I <sub>DM</sub>	90	A	
Pulsed Body Diode Forward Current (10μs Pulse, Duty Cycle = 1%)	I <sub>SM</sub>	90	A	
Avalanche Current, L = 0.1mH	I <sub>AS</sub>	19	A	
Avalanche Energy, L = 0.1mH	E <sub>AS</sub>	19	mJ	

**Thermal Characteristics** (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Value	Unit
Total Power Dissipation (Note 5)	P <sub>D</sub>	2.3	W
Thermal Resistance, Junction to Ambient (Note 5)	R <sub>θJA</sub>	55	°C/W
Total Power Dissipation (Note 8)	P <sub>D</sub>	35.7	W
Thermal Resistance, Junction to Case (Note 8)	R <sub>θJC</sub>	3.5	°C/W
Operating and Storage Temperature Range	T <sub>J</sub> , T <sub>STG</sub>	-55 to +150	°C

**Electrical Characteristics** (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
<b>OFF CHARACTERISTICS (Note 6)</b>						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	30	-	-	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	-	-	1	μA	V <sub>DS</sub> = 24V, V <sub>GS</sub> = 0V
Gate-Source Leakage	I <sub>GSS</sub>	-	-	±100	nA	V <sub>GS</sub> = ±16V, V <sub>DS</sub> = 0V
<b>ON CHARACTERISTICS (Note 6)</b>						
Gate Threshold Voltage	V <sub>GS(TH)</sub>	1	-	3	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA
Static Drain-Source On-Resistance	R <sub>DS(ON)</sub>	-	6.6	11	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 14.4A
		-	10.5	13		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 7A
		-	13.4	20		V <sub>GS</sub> = 3.8V, I <sub>D</sub> = 5A
Diode Forward Voltage	V <sub>SD</sub>	-	0.8	1.2	V	V <sub>GS</sub> = 0V, I <sub>S</sub> = 10A
<b>DYNAMIC CHARACTERISTICS (Note 7)</b>						
Input Capacitance	C <sub>iss</sub>	-	823	-	pF	V <sub>DS</sub> = 15V, V <sub>GS</sub> = 0V, f = 1.0MHz
Output Capacitance	C <sub>oss</sub>	-	352	-	pF	
Reverse Transfer Capacitance	C <sub>rss</sub>	-	52	-	pF	
Gate Resistance	R <sub>g</sub>	-	1.2	-	Ω	V <sub>DS</sub> = 0V, V <sub>GS</sub> = 0V, f = 1.0MHz
Total Gate Charge (V <sub>GS</sub> = 4.5V)	Q <sub>g</sub>	-	5.8	-	nC	V <sub>DS</sub> = 15V, I <sub>D</sub> = 14.4A
Total Gate Charge (V <sub>GS</sub> = 10V)	Q <sub>g</sub>	-	12	-	nC	
Gate-Source Charge	Q <sub>gs</sub>	-	1.7	-	nC	
Gate-Drain Charge	Q <sub>gd</sub>	-	2.4	-	nC	
Turn-On Delay Time	t <sub>D(ON)</sub>	-	3.2	-	ns	V <sub>GS</sub> = 10V, V <sub>DD</sub> = 15V, R <sub>G</sub> = 1Ω, I <sub>D</sub> = 10A
Turn-On Rise Time	t <sub>r</sub>	-	5.2	-	ns	
Turn-Off Delay Time	t <sub>D(OFF)</sub>	-	8.9	-	ns	
Turn-Off Fall Time	t <sub>f</sub>	-	1.5	-	ns	
Body Diode Reverse Recovery Time	t <sub>RR</sub>	-	16.4	-	ns	I <sub>F</sub> = 10A, dI/dt = 100A/μs
Body Diode Reverse Recovery Charge	Q <sub>R</sub>	-	5.9	-	nC	

- Notes:
- Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1inch square copper plate.
  - Short duration pulse test used to minimize self-heating effect.
  - Guaranteed by design. Not subject to product testing.
  - Thermal resistance from junction to soldering point (on the exposed drain pad).

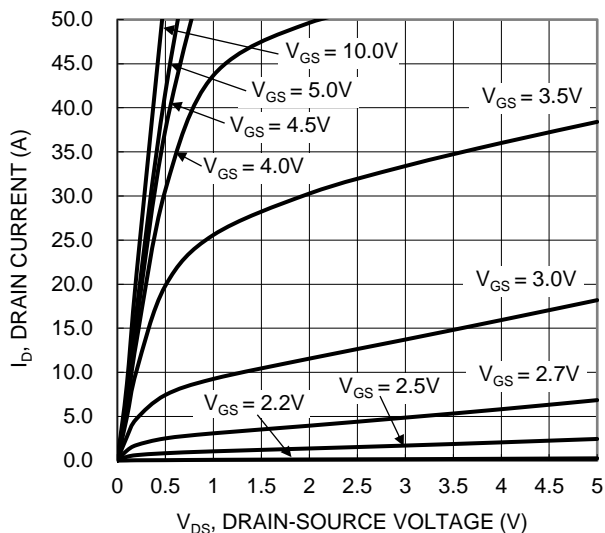


Figure 1. Typical Output Characteristic

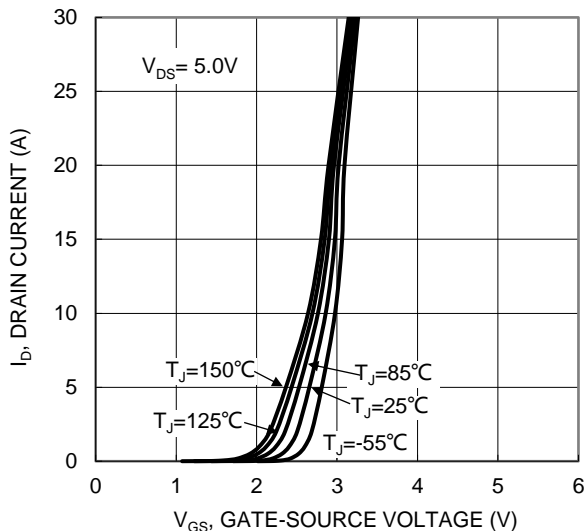


Figure 2. Typical Transfer Characteristic

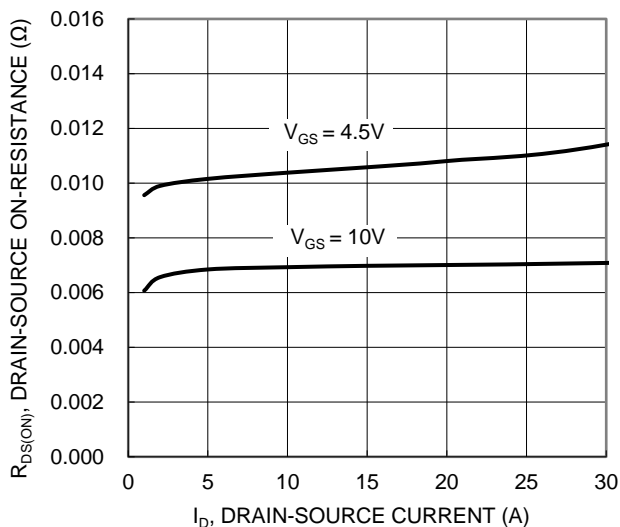


Figure 3. Typical On-Resistance vs. Drain Current and Gate Voltage

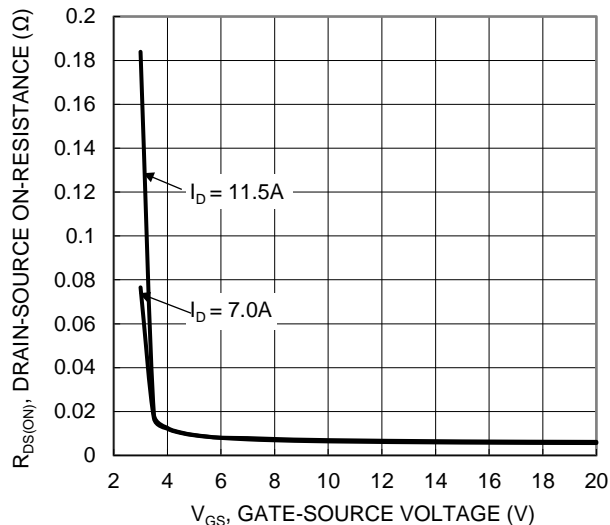


Figure 4. Typical Transfer Characteristic

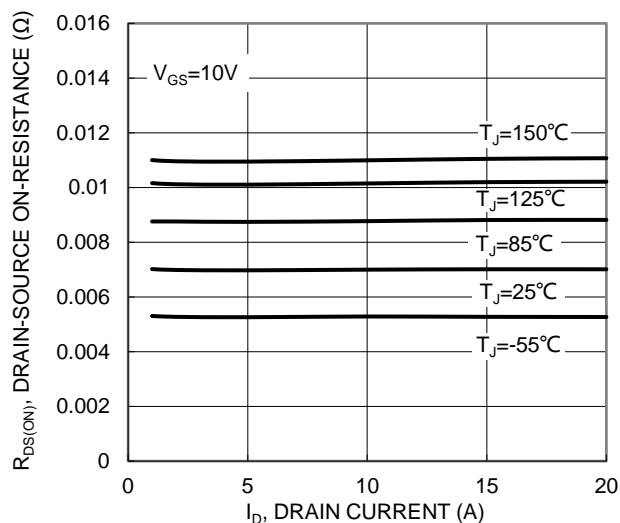


Figure 5. Typical On-Resistance vs. Drain Current and Temperature

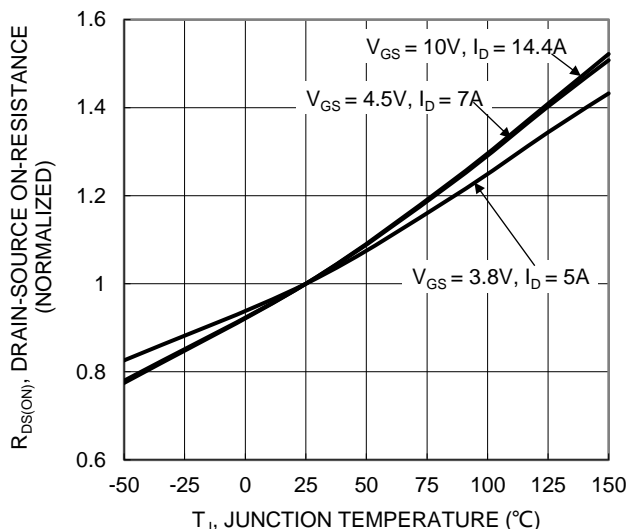


Figure 6. On-Resistance Variation with Temperature

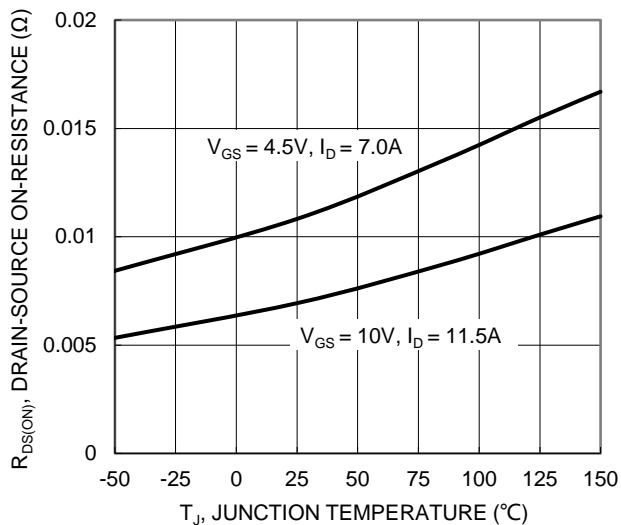


Figure 7. On-Resistance Variation with Temperature

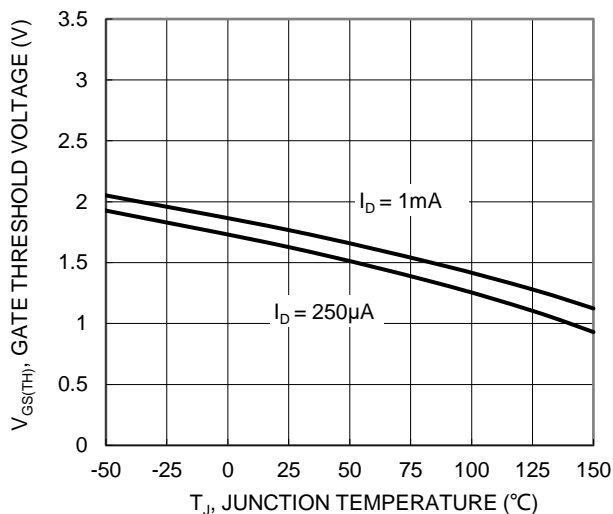


Figure 8. Gate Threshold Variation vs Junction Temperature

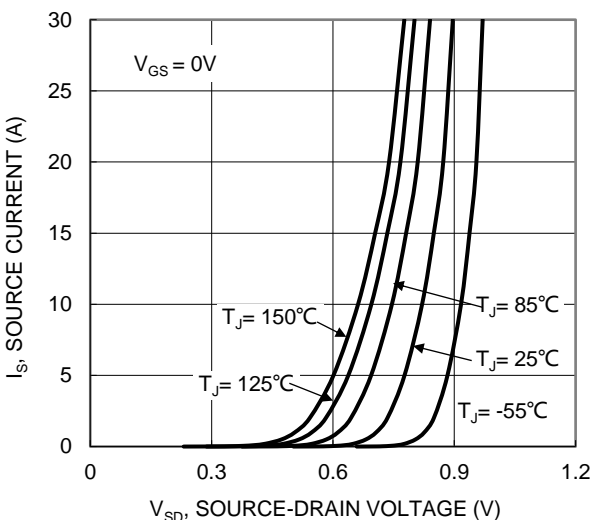


Figure 9. Diode Forward Voltage vs. Current

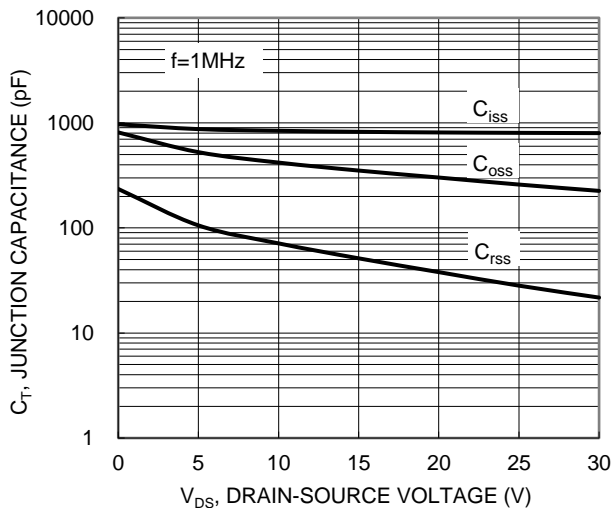


Figure 10. Typical Junction Capacitance

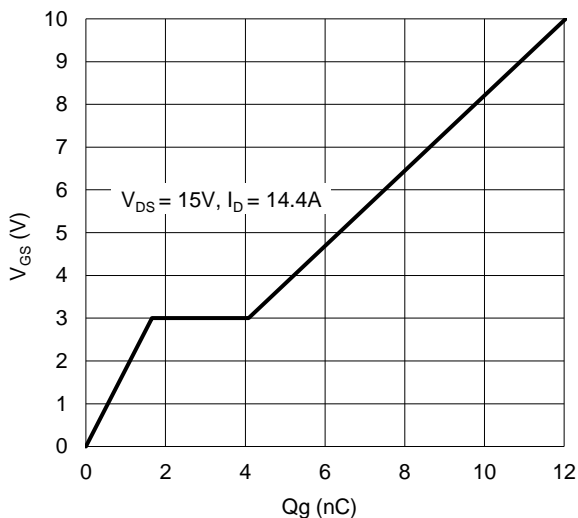


Figure 11. Gate Charge

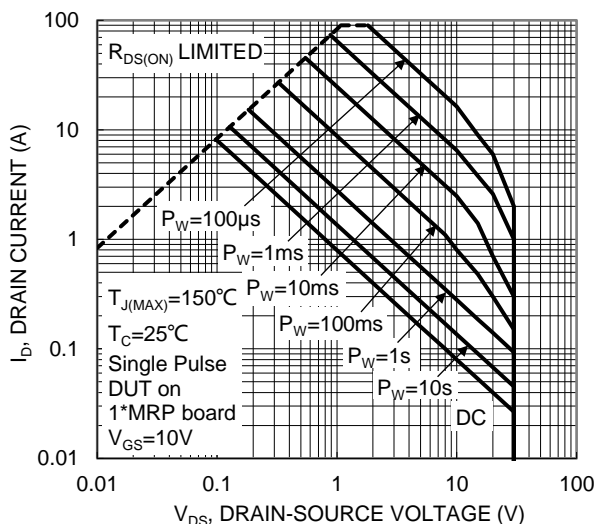


Figure 12. SOA, Safe Operation Area

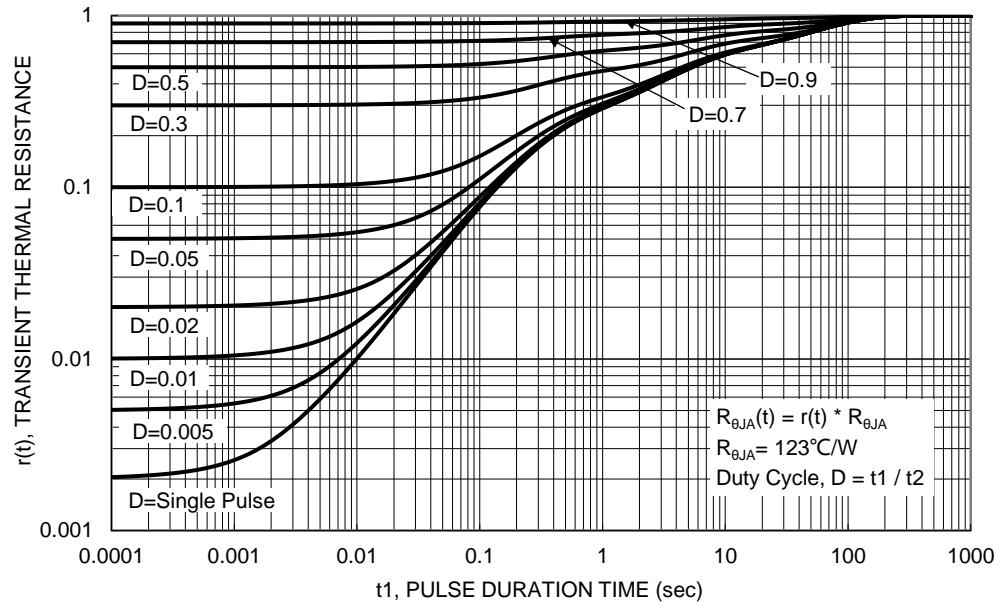


Figure 13. Transient Thermal Resistance

